

Notice of References Cited	Application/Control No. 10/635,649		Applicant(s)/Patent Under Reexamination HATADE ET AL.	
	Examiner VAN T. PHAM		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,728,193	04-2004	Uchizaki et al.	369/112.01
*	B	US-2001/0000310	04-2001	Yoo et al.	369/112.26
*	C	US-7,075,880	07-2006	Honda et al.	369/112.08
*	D	US-6,118,749	09-2000	Arai et al.	369/112.26
*	E	US-2002/0150035	10-2002	Bernacki et al.	369/300
*	F	US-7,177,259	02-2007	Nishi et al.	369/112.16
*	G	US-5,956,259	09-1999	Hartsell et al.	700/302
*	H	US-5,404,009	04-1995	Kando et al.	250/227.24
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.